

Ryszard Jablonski

List of Publications by Year in descending order

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Version: 2024-02-01

9
papers

236
citations

1307594

7
h-index

1474206

9
g-index

10
all docs

10
docs citations

10
times ranked

139
citing authors

#	ARTICLE	IF	CITATIONS
1	Single-Electron Transport through Single Dopants in a Dopant-Rich Environment. Physical Review Letters, 2010, 105, 016803.	7.8	90
2	Observation of individual dopants in a thin silicon layer by low temperature Kelvin Probe Force Microscope. Applied Physics Letters, 2008, 93, .	3.3	61
3	Effects of deep-level dopants on the electronic potential of thin Si <i>pn</i> junctions observed by Kelvin probe force microscope. Applied Physics Letters, 2013, 102, .	3.3	22
4	Effect of electron injection into phosphorus donors in silicon-on-insulator channel observed by Kelvin probe force microscopy. Applied Physics Letters, 2011, 99, .	3.3	21
5	Comparative study of donor-induced quantum dots in Si nano-channels by single-electron transport characterization and Kelvin probe force microscopy. Journal of Applied Physics, 2015, 117, .	2.5	16
6	Tunneling in Systems of Coupled Dopant-Atoms in Silicon Nano-devices. Nanoscale Research Letters, 2015, 10, 372.	5.7	11
7	Development of an XYZ Digital Camera with Embedded Color Calibration System for Accurate Color Acquisition. IEICE Transactions on Information and Systems, 2010, E93-D, 651-653.	0.7	10
8	Single-Electron Charging in Phosphorus Donors in Silicon Observed by Low-Temperature Kelvin Probe Force Microscope. Japanese Journal of Applied Physics, 2011, 50, 08LB10.	1.5	3
9	3D imaging of intrinsic crystalline defects in zinc oxide by spectrally resolved two-photon fluorescence microscopy. Applied Physics Letters, 2017, 110, .	3.3	2